

Notice of References Cited	Application/Control No. 10/520,439	Applicant(s)/Patent Under Reexamination MAYES ET AL.	
	Examiner ALEX NOGUEROLA	Art Unit 1795	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gopal et al. "Electrochemical Capacitance Voltage Profiling of the Narrow Band Gap Semiconductor InAs, " Journal of Electronic Materials, vol. 29, No. 11, 2000
	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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